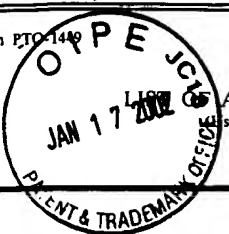
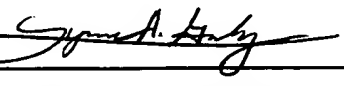


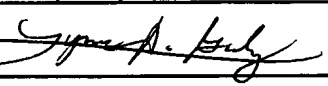


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|  PART CITED BY APPLICANT (Use several sheets if necessary) | | | | APPLICANT Wendell P. Noble | | | |
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| U.S. PATENT DOCUMENTS | | | | | | | |
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| | | Document Number | Date | Country | Class | Subclass | Translation |
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| | AM | 0 720 221 A1 | 07/03/96 | EPO | | | |
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| | AQ | | | | | | |
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| | AR | | Kuge et al., <i>SOI-DRAM Circuit Technologies For Low Power High Speed Multigiga Scale Memories</i> , IEEE Journal of Solid State Circuits, April 1996, pp. 586-591. | | | | |
| | AS | | Suma et al., <i>An SOI-DRAM With Wide Operating Voltage Range by CMOS/SIMOX Technology</i> , IEEE Journal of Solid State Circuits, November 1994, pp. 1323-1329. | | | | |
| | AT | | Bakeman et al., <i>A High Performance 16-Mb DRAM Technology</i> , 1990 Symposium on VLSI Technology Digest of Technical Papers, Honolulu, HI, June 4-7, pp. 11-12. | | | | |
| EXAMINER  | | | | DATE CONSIDERED 8/26/02 | | | |
| *EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. | | | | | | | |

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| LIST OF ART CITED BY APPLICANT (Use several sheets if necessary) | | | | APPLICANT Wendell P. Noble | | |
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| *EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. | | | | | | |

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| LIST OF ART CITED BY APPLICANT (Use several sheets if necessary) | | | | APPLICANT Wendell P. Noble | | PRIORITY FILING DATE May 11, 1999 | |
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| U.S. PATENT DOCUMENTS | | | | | | | |
| *Examiner Initial | Document Number | Date | Name | Class | Subclass | Filing Date If Appropriate | |
| <i>JL</i> | AA | 4,604,162 | 08/1986 | Sobczak | 156 | 657 | — |
| <i>JL</i> | AB | 4,700,461 | 10/1987 | Choi et al. | 437 | 416 | — |
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| <i>JL</i> | AE | 5,391,911 | 02/1995 | Beyer et al. | 257 | 522 | — |
| <i>JL</i> | AF | 5,539,229 | 07/1996 | Noble, Jr. et al. | 257 | 301 | — |
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| <i>JL</i> | AH | 5,608,248 | 03/1997 | Ohno | 257 | 306 | — |
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| <i>JL</i> | AK | 5,846,854 | 12/1998 | Giraud et al. | 438 | 149 | — |
| <i>JL</i> | AL | 6,004,865 | 12/1999 | Horiuchi et al. | | | — |
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| *Examiner Initial | | Document Number | Date | Name | Class | Subclass | Filing Date If Appropriate |
|-------------------|----|-----------------|---------|----------------|-------|----------|----------------------------|
| <i>CB</i> | AA | 6,091,129 | 07/2000 | Cleeves | | | |
| <i>CB</i> | AB | 6,117,760 | 09/2000 | Gardner et al. | | | |
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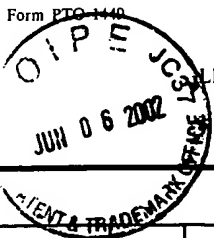
G. H. Hardy

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| *Examiner Initial | | Document Number | Date | Name | Class | Subclass | Filing Date If Appropriate |
|-------------------|----|-----------------|----------|------|-------|----------|----------------------------|
| <i>JS</i> | AA | 6,274,919 | 08/14/01 | Wada | | | |
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

| | | |
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| <i>JS</i> | AR | Article: SEPIA: A New Isolation Structure for Soft-Error-Immune LSI's (February 1993) |
| | AS | |
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